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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	HDMI-CEC, I <sup>2</sup> C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I <sup>2</sup> S, POR, PWM, WDT
Number of I/O	50
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 19x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-UFBGA
Supplier Device Package	64-UFBGA (5x5)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f078rbh7tr">https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f078rbh7tr</a>

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- **Stop mode**

Stop mode achieves very low power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled.

The device can be woken up from Stop mode by any of the EXTI lines. The EXTI line source can be one of the 16 external lines, RTC, I2C1, USART1, USART2, USB, COMPx, V<sub>DDIO2</sub> supply comparator or the CEC.

The CEC, USART1, USART2 and I2C1 peripherals can be configured to enable the HSI RC oscillator so as to get clock for processing incoming data.

*Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop mode.*

## 3.6 Clocks and startup

System clock selection is performed on startup, however the internal RC 8 MHz oscillator is selected as default CPU clock on reset. An external 4-32 MHz clock can be selected, in which case it is monitored for failure. If failure is detected, the system automatically switches back to the internal RC oscillator. A software interrupt is generated if enabled. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example on failure of an indirectly used external crystal, resonator or oscillator).

Several prescalers allow the application to configure the frequency of the AHB and the APB domains. The maximum frequency of the AHB and the APB domains is 48 MHz.

Additionally, also the internal RC 48 MHz oscillator can be selected for system clock or PLL input source. This oscillator can be automatically fine-trimmed by the means of the CRS peripheral using the external synchronization.

sensor, voltage reference, VBAT voltage measurement) channels and performs conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADC can be served by the DMA controller.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

### 3.10.1 Temperature sensor

The temperature sensor (TS) generates a voltage  $V_{\text{SENSE}}$  that varies linearly with temperature.

The temperature sensor is internally connected to the ADC\_IN16 input channel which is used to convert the sensor output voltage into a digital value.

The sensor provides good linearity but it has to be calibrated to obtain good overall accuracy of the temperature measurement. As the offset of the temperature sensor varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

**Table 2. Temperature sensor calibration values**

Calibration value name	Description	Memory address
TS_CAL1	TS ADC raw data acquired at a temperature of 30 °C ( $\pm 5$ °C), $V_{\text{DDA}} = 3.3$ V ( $\pm 10$ mV)	0x1FFF F7B8 - 0x1FFF F7B9
TS_CAL2	TS ADC raw data acquired at a temperature of 110 °C ( $\pm 5$ °C), $V_{\text{DDA}} = 3.3$ V ( $\pm 10$ mV)	0x1FFF F7C2 - 0x1FFF F7C3

### 3.10.2 Internal voltage reference ( $V_{\text{REFINT}}$ )

The internal voltage reference ( $V_{\text{REFINT}}$ ) provides a stable (bandgap) voltage output for the ADC and comparators.  $V_{\text{REFINT}}$  is internally connected to the ADC\_IN17 input channel. The precise voltage of  $V_{\text{REFINT}}$  is individually measured for each part by ST during production test and stored in the system memory area. It is accessible in read-only mode.

**Table 3. Internal voltage reference calibration values**

Calibration value name	Description	Memory address
VREFINT_CAL	Raw data acquired at a temperature of 30 °C ( $\pm 5$ °C), $V_{\text{DDA}} = 3.3$ V ( $\pm 10$ mV)	0x1FFF F7BA - 0x1FFF F7BB

TIM15 can be synchronized with TIM16 and TIM17.

TIM15, TIM16 and TIM17 have a complementary output with dead-time generation and independent DMA request generation.

Their counters can be frozen in debug mode.

### 3.14.3 Basic timers TIM6 and TIM7

These timers are mainly used for DAC trigger generation. They can also be used as generic 16-bit time bases.

### 3.14.4 Independent watchdog (IWDG)

The independent watchdog is based on an 8-bit prescaler and 12-bit downcounter with user-defined refresh window. It is clocked from an independent 40 kHz internal RC and as it operates independently from the main clock, it can operate in Stop mode. It can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

### 3.14.5 System window watchdog (WWDG)

The system window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the APB clock (PCLK). It has an early warning interrupt capability and the counter can be frozen in debug mode.

### 3.14.6 SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- a 24-bit down counter
- autoreload capability
- maskable system interrupt generation when the counter reaches 0
- programmable clock source (HCLK or HCLK/8)

## 3.15 Real-time clock (RTC) and backup registers

The RTC and the five backup registers are supplied through a switch that takes power either on  $V_{DD}$  supply when present or through the  $V_{BAT}$  pin. The backup registers are five 32-bit registers used to store 20 bytes of user application data when  $V_{DD}$  power is not present. They are not reset by a system or power reset.

Figure 7. UFQFPN48 package pinout

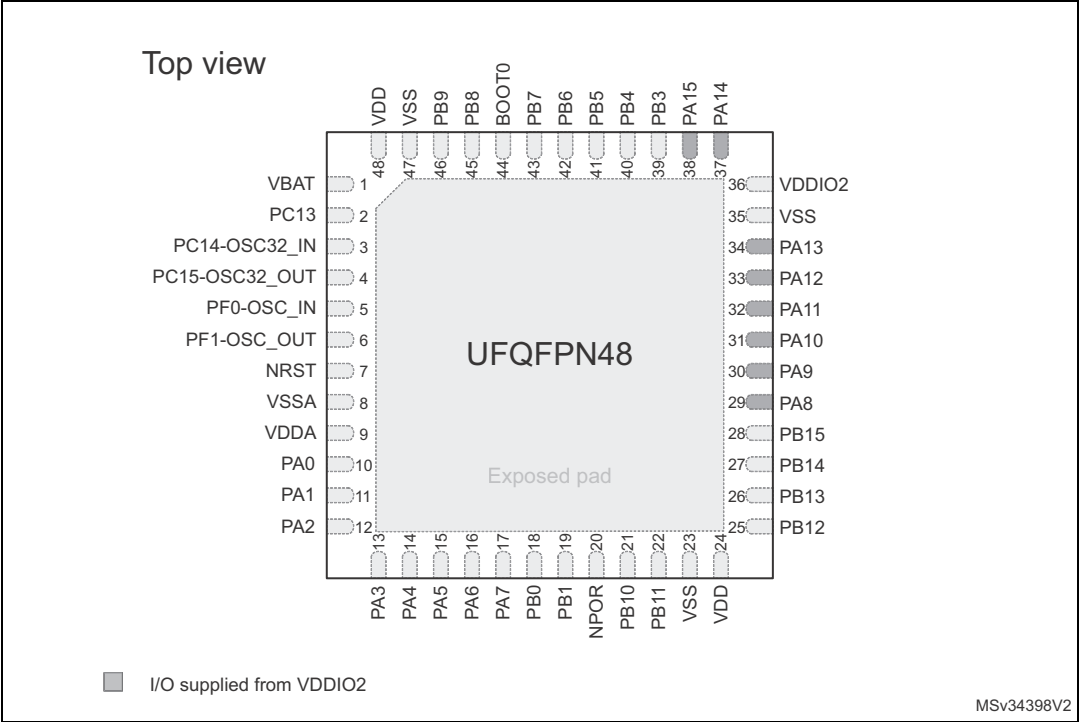
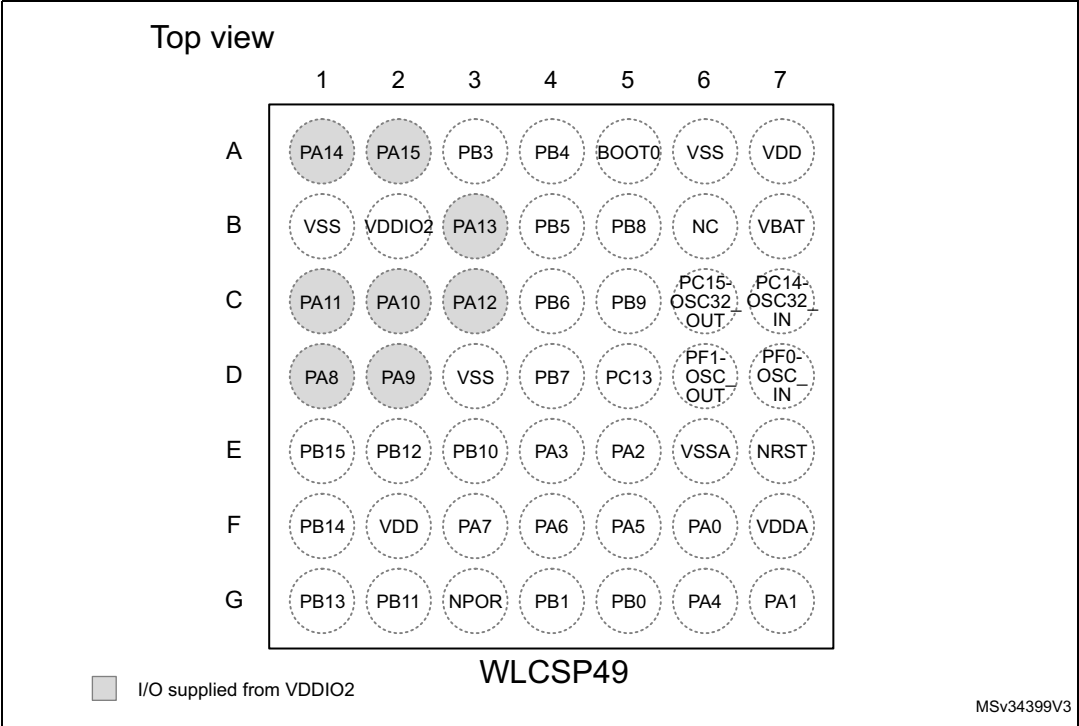


Figure 8. WLCSP49 package pinout



1. The above figure shows the package in top view, changing from bottom view in the previous document versions.

Table 12. STM32F078CB/RB/VB pin definitions (continued)

Pin numbers					Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	LQFP64	LQFP48/UQFPN48	WLCSP49					Alternate functions	Additional functions
C1	7	2	2	D5	PC13	I/O	TC	(1) (2)	-	WKUP2, RTC_TAMP1, RTC_TS, RTC_OUT
D1	8	3	3	C7	PC14-OSC32_IN (PC14)	I/O	TC	(1) (2)	-	OSC32_IN
E1	9	4	4	C6	PC15- OSC32_OUT (PC15)	I/O	TC	(1) (2)	-	OSC32_OUT
F2	10	-	-	-	PF9	I/O	FT	-	TIM15_CH1	-
G2	11	-	-	-	PF10	I/O	FT	-	TIM15_CH2	-
F1	12	5	5	D7	PF0-OSC_IN (PF0)	I/O	FT	-	CRS_SYNC	OSC_IN
G1	13	6	6	D6	PF1-OSC_OUT (PF1)	I/O	FT	-	-	OSC_OUT
H2	14	7	7	E7	NRST	I/O	RST	-	Device reset input / internal reset output (active low)	
H1	15	8	-	-	PC0	I/O	TTa	-	EVENTOUT	ADC_IN10
J2	16	9	-	-	PC1	I/O	TTa	-	EVENTOUT	ADC_IN11
J3	17	10	-	-	PC2	I/O	TTa	-	SPI2_MISO, I2S2_MCK, EVENTOUT	ADC_IN12
K2	18	11	-	-	PC3	I/O	TTa	-	SPI2_MOSI, I2S2_SD, EVENTOUT	ADC_IN13
J1	19	-	-	-	PF2	I/O	FT	-	EVENTOUT	WKUP8
K1	20	12	8	E6	VSSA	S	-	-	Analog ground	
M1	21	13	9	F7	VDDA	S	-	-	Analog power supply	
L1	22	-	-	-	PF3	I/O	FT	-	EVENTOUT	
L2	23	14	10	F6	PA0	I/O	TTa	-	USART2_CTS, TIM2_CH1_ETR, TSC_G1_IO1, USART4_TX	RTC_TAMP2, WKUP1, COMP1_OUT, ADC_IN0, COMP1_INM6

Table 12. STM32F078CB/RB/VB pin definitions (continued)

Pin numbers					Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	LQFP64	LQFP48/UQFPN48	WLCSP49					Alternate functions	Additional functions
A7	90	56	40	A4	PB4	I/O	FT	-	SPI1_MISO, I2S1_MCK, TIM17_BKIN, TIM3_CH1, TSC_G5_IO2, EVENTOUT	-
C5	91	57	41	B4	PB5	I/O	FT	-	SPI1_MOSI, I2S1_SD, I2C1_SMBA, TIM16_BKIN, TIM3_CH2	WKUP6
B5	92	58	42	C4	PB6	I/O	FTf	-	I2C1_SCL, USART1_TX, TIM16_CH1N, TSC_G5_IO3	-
B4	93	59	43	D4	PB7	I/O	FTf	-	I2C1_SDA, USART1_RX, USART4_CTS, TIM17_CH1N, TSC_G5_IO4	-
A4	94	60	44	A5	BOOT0	I	B	-	Boot memory selection	
A3	95	61	45	B5	PB8	I/O	FTf	-	I2C1_SCL, CEC, TIM16_CH1, TSC_SYNC	-
B3	96	62	46	C5	PB9	I/O	FTf	-	SPI2_NSS, I2S2_WS, I2C1_SDA, IR_OUT, TIM17_CH1, EVENTOUT	-
C3	97	-	-	-	PE0	I/O	FT	-	EVENTOUT, TIM16_CH1	-
A2	98	-	-	-	PE1	I/O	FT	-	EVENTOUT, TIM17_CH1	-
D3	99	63	47	A6	VSS	S	-	-	Ground	
C4	100	64	48	A7	VDD	S	-	-	Digital power supply	

- PC13, PC14 and PC15 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 in output mode is limited:
  - The speed should not exceed 2 MHz with a maximum load of 30 pF.
  - These GPIOs must not be used as current sources (e.g. to drive an LED).
- After the first RTC domain power-up, PC13, PC14 and PC15 operate as GPIOs. Their function then depends on the content of the RTC registers which are not reset by the system reset. For details on how to manage these GPIOs, refer to the RTC domain and RTC register descriptions in the reference manual.
- This pin is supplied by  $V_{DDA}$ .
- PC6, PC7, PC8, PC9, PA8, PA9, PA10, PA11, PA12, PA13, PF6, PA14, PA15, PC10, PC11, PC12, PD0, PD1 and PD2 I/Os are supplied by VDDIO2.
- After reset, these pins are configured as SWDIO and SWCLK alternate functions, and the internal pull-up on the SWDIO pin and the internal pull-down on the SWCLK pin are activated.

Table 15. Alternate functions selected through GPIOC\_AFR registers for port C

Pin name	AF0	AF1
PC0	EVENTOUT	-
PC1	EVENTOUT	-
PC2	EVENTOUT	SPI2_MISO, I2S2_MCK
PC3	EVENTOUT	SPI2_MOSI, I2S2_SD
PC4	EVENTOUT	USART3_TX
PC5	TSC_G3_IO1	USART3_RX
PC6	TIM3_CH1	-
PC7	TIM3_CH2	-
PC8	TIM3_CH3	-
PC9	TIM3_CH4	-
PC10	USART4_TX	USART3_TX
PC11	USART4_RX	USART3_RX
PC12	USART4_CK	USART3_CK
PC13	-	-
PC14	-	-
PC15	-	-

Table 16. Alternate functions selected through GPIOD\_AFR registers for port D

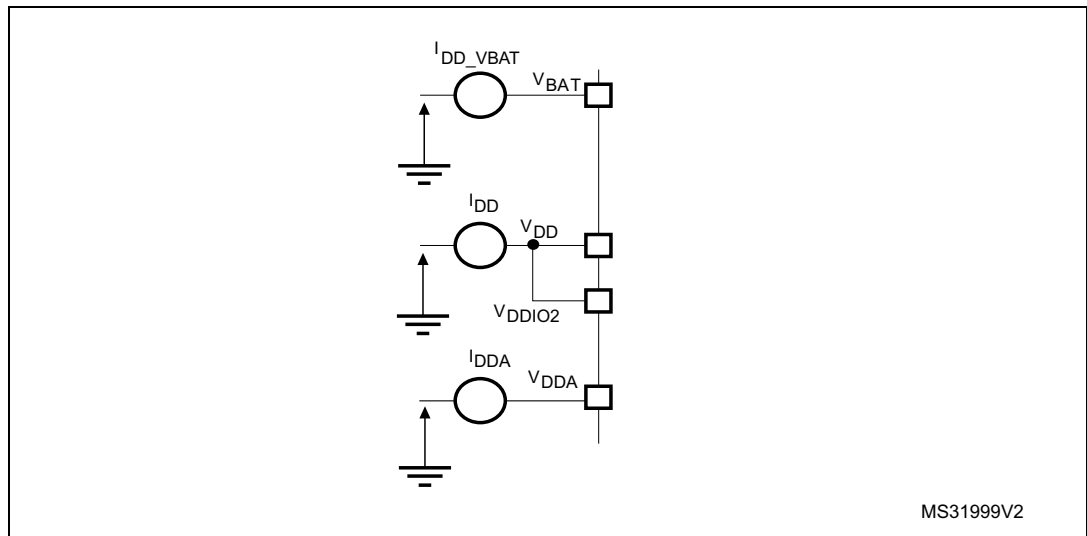
Pin name	AF0	AF1
PD0	-	SPI2_NSS, I2S2_WS
PD1	-	SPI2_SCK, I2S2_CK
PD2	TIM3_ETR	USART3_RTS
PD3	USART2_CTS	SPI2_MISO, I2S2_MCK
PD4	USART2_RTS	SPI2_MOSI, I2S2_SD
PD5	USART2_TX	-
PD6	USART2_RX	-
PD7	USART2_CK	-
PD8	USART3_TX	-
PD9	USART3_RX	-
PD10	USART3_CK	-
PD11	USART3_CTS	-
PD12	USART3_RTS	TSC_G8_IO1
PD13	-	TSC_G8_IO2
PD14	-	TSC_G8_IO3
PD15	CRS_SYNC	TSC_G8_IO4

Table 19. STM32F078CB/RB/VB peripheral register boundary addresses (continued)

Bus	Boundary address	Size	Peripheral
APB	0x4000 7C00 - 0x4000 7FFF	1 KB	Reserved
	0x4000 7800 - 0x4000 7BFF	1 KB	CEC
	0x4000 7400 - 0x4000 77FF	1 KB	DAC
	0x4000 7000 - 0x4000 73FF	1 KB	PWR
	0x4000 6C00 - 0x4000 6FFF	1 KB	CRS
	0x4000 6400 - 0x4000 6BFF	2 KB	Reserved
	0x4000 6000 - 0x4000 63FF	1 KB	USB RAM
	0x4000 5C00 - 0x4000 5FFF	1 KB	USB
	0x4000 5800 - 0x4000 5BFF	1 KB	I2C2
	0x4000 5400 - 0x4000 57FF	1 KB	I2C1
	0x4000 5000 - 0x4000 53FF	1 KB	Reserved
	0x4000 4C00 - 0x4000 4FFF	1 KB	USART4
	0x4000 4800 - 0x4000 4BFF	1 KB	USART3
	0x4000 4400 - 0x4000 47FF	1 KB	USART2
	0x4000 3C00 - 0x4000 43FF	2 KB	Reserved
	0x4000 3800 - 0x4000 3BFF	1 KB	SPI2
	0x4000 3400 - 0x4000 37FF	1 KB	Reserved
	0x4000 3000 - 0x4000 33FF	1 KB	IWDG
	0x4000 2C00 - 0x4000 2FFF	1 KB	WWDG
	0x4000 2800 - 0x4000 2BFF	1 KB	RTC
	0x4000 2400 - 0x4000 27FF	1 KB	Reserved
	0x4000 2000 - 0x4000 23FF	1 KB	TIM14
	0x4000 1800 - 0x4000 1FFF	2 KB	Reserved
	0x4000 1400 - 0x4000 17FF	1 KB	TIM7
	0x4000 1000 - 0x4000 13FF	1 KB	TIM6
	0x4000 0800 - 0x4000 0FFF	2 KB	Reserved
	0x4000 0400 - 0x4000 07FF	1 KB	TIM3
	0x4000 0000 - 0x4000 03FF	1 KB	TIM2

### 6.1.7 Current consumption measurement

Figure 13. Current consumption measurement scheme



### Typical and maximum current consumption

The MCU is placed under the following conditions:

- All I/O pins are in analog input mode
- All peripherals are disabled except when explicitly mentioned
- The Flash memory access time is adjusted to the  $f_{HCLK}$  frequency:
  - 0 wait state and Prefetch OFF from 0 to 24 MHz
  - 1 wait state and Prefetch ON above 24 MHz
- When the peripherals are enabled  $f_{PCLK} = f_{HCLK}$

The parameters given in [Table 26](#) to [Table 30](#) are derived from tests performed under ambient temperature and supply voltage conditions summarized in [Table 23: General operating conditions](#).

**Table 26. Typical and maximum current consumption from  $V_{DD}$  supply at  $V_{DD} = 1.8$  V**

Symbol	Parameter	Conditions	f <sub>HCLK</sub>	All peripherals enabled <sup>(1)</sup>				All peripherals disabled				Unit
				Typ	Max @ T <sub>A</sub> <sup>(2)</sup>			Typ	Max @ T <sub>A</sub> <sup>(2)</sup>			
					25 °C	85 °C	105 °C		25 °C	85 °C	105 °C	
I <sub>DD</sub>	Supply current in Run mode, code executing from Flash memory	HSI48	48 MHz	23.0	24.8	25.8	26.7	12.9	13.7	14.1	15.3	mA
		HSE bypass, PLL on	48 MHz	22.9	24.6	25.7	26.6	12.8	13.6	13.9	15.2	
			32 MHz	15.5	16.6	17.2	19.1	8.7	9.2	9.4	10.0	
			24 MHz	12.0	12.8	13.2	14.3	6.8	7.2	7.3	7.7	
		HSE bypass, PLL off	8 MHz	4.2	4.4	4.5	4.6	2.4	2.6	2.6	2.7	
			1 MHz	0.7	0.9	1.0	1.1	0.5	0.6	0.7	0.7	
		HSI clock, PLL on	48 MHz	22.9	24.6	25.7	27.6	12.8	13.6	13.9	15.2	
			32 MHz	15.5	16.6	17.2	19.1	8.7	9.2	9.4	10.0	
			24 MHz	12.0	12.8	13.2	14.3	6.8	7.2	7.3	7.7	
		HSI clock, PLL off	8 MHz	4.2	4.4	4.5	4.6	2.4	2.6	2.6	2.7	

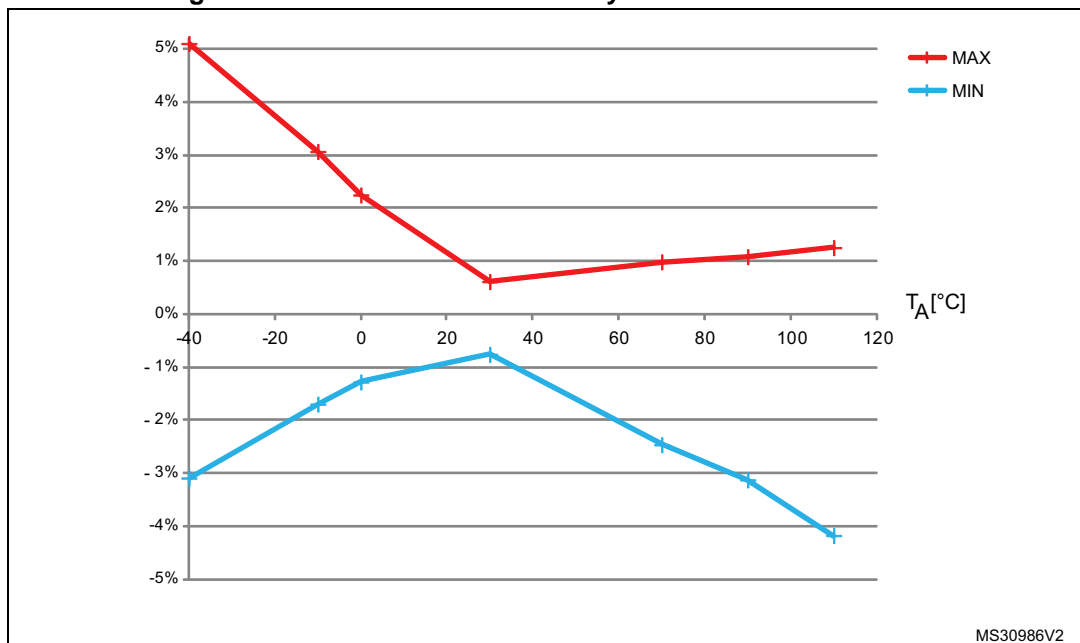
## High-speed internal 14 MHz (HSI14) RC oscillator (dedicated to ADC)

Table 39. HSI14 oscillator characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{HSI14}}$	Frequency	-	-	14	-	MHz
TRIM	HSI14 user-trimming step	-	-	-	1 <sup>(2)</sup>	%
DuCy <sub>(HSI14)</sub>	Duty cycle	-	45 <sup>(2)</sup>	-	55 <sup>(2)</sup>	%
ACC <sub>HSI14</sub>	Accuracy of the HSI14 oscillator (factory calibrated)	$T_A = -40 \text{ to } 105 \text{ }^\circ\text{C}$	-4.2 <sup>(3)</sup>	-	5.1 <sup>(3)</sup>	%
		$T_A = -10 \text{ to } 85 \text{ }^\circ\text{C}$	-3.2 <sup>(3)</sup>	-	3.1 <sup>(3)</sup>	%
		$T_A = 0 \text{ to } 70 \text{ }^\circ\text{C}$	-2.5 <sup>(3)</sup>	-	2.3 <sup>(3)</sup>	%
		$T_A = 25 \text{ }^\circ\text{C}$	-1	-	1	%
$t_{\text{su(HSI14)}}$	HSI14 oscillator startup time	-	1 <sup>(2)</sup>	-	2 <sup>(2)</sup>	$\mu\text{s}$
$I_{\text{DDA(HSI14)}}$	HSI14 oscillator power consumption	-	-	100	150 <sup>(2)</sup>	$\mu\text{A}$

1.  $V_{\text{DDA}} = 3.3 \text{ V}$ ,  $T_A = -40 \text{ to } 105 \text{ }^\circ\text{C}$  unless otherwise specified.
2. Guaranteed by design, not tested in production.
3. Data based on characterization results, not tested in production.

Figure 19. HSI14 oscillator accuracy characterization results



## High-speed internal 48 MHz (HSI48) RC oscillator

Table 40. HSI48 oscillator characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{HSI48}}$	Frequency	-	-	48	-	MHz
TRIM	HSI48 user-trimming step	-	0.09 <sup>(2)</sup>	0.14	0.2 <sup>(2)</sup>	%
DuCy <sub>(HSI48)</sub>	Duty cycle	-	45 <sup>(2)</sup>	-	55 <sup>(2)</sup>	%
$\text{ACC}_{\text{HSI48}}$	Accuracy of the HSI48 oscillator (factory calibrated)	$T_A = -40 \text{ to } 105 \text{ }^\circ\text{C}$	-4.9 <sup>(3)</sup>	-	4.7 <sup>(3)</sup>	%
		$T_A = -10 \text{ to } 85 \text{ }^\circ\text{C}$	-4.1 <sup>(3)</sup>	-	3.7 <sup>(3)</sup>	%
		$T_A = 0 \text{ to } 70 \text{ }^\circ\text{C}$	-3.8 <sup>(3)</sup>	-	3.4 <sup>(3)</sup>	%
		$T_A = 25 \text{ }^\circ\text{C}$	-2.8	-	2.9	%
$t_{\text{su(HSI48)}}$	HSI48 oscillator startup time	-	-	-	6 <sup>(2)</sup>	$\mu\text{s}$
$I_{\text{DDA(HSI48)}}$	HSI48 oscillator power consumption	-	-	312	350 <sup>(2)</sup>	$\mu\text{A}$

1.  $V_{\text{DDA}} = 3.3 \text{ V}$ ,  $T_A = -40 \text{ to } 105 \text{ }^\circ\text{C}$  unless otherwise specified.
2. Guaranteed by design, not tested in production.
3. Data based on characterization results, not tested in production.

Figure 20. HSI48 oscillator accuracy characterization results

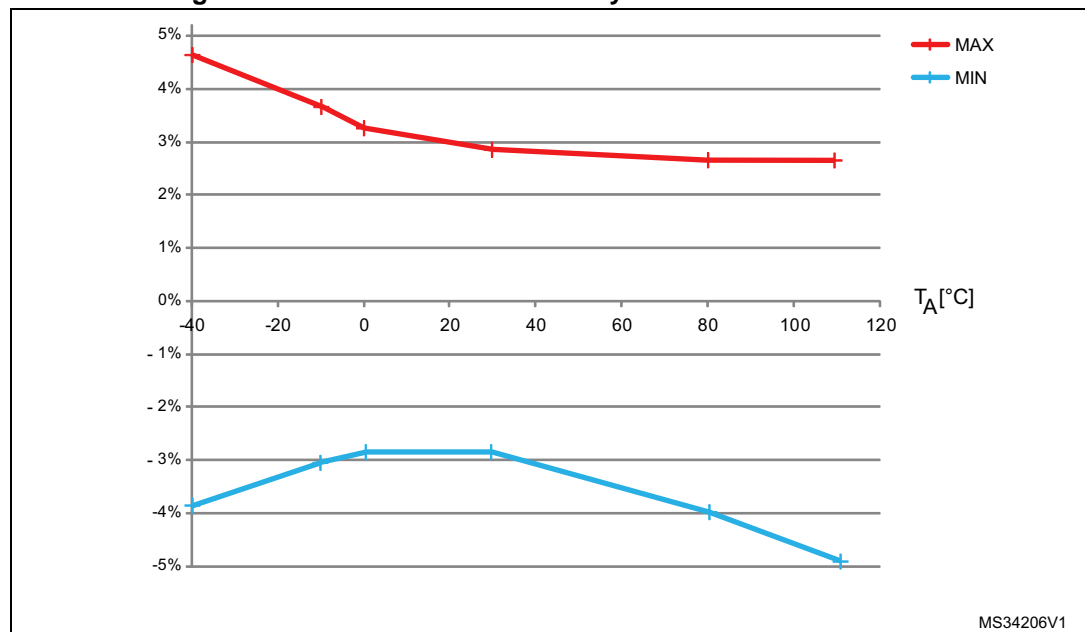


Table 47. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Packages	Class	Maximum value <sup>(1)</sup>	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	$T_A = +25\text{ }^{\circ}\text{C}$ , conforming to JESD22-A114	All	2	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)	$T_A = +25\text{ }^{\circ}\text{C}$ , conforming to ANSI/ESD STM5.3.1	WLCSP49	C3	250	V
			All others	C4	500	

1. Data based on characterization results, not tested in production.

### Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin.
- A current injection is applied to each input, output and configurable I/O pin.

These tests are compliant with EIA/JESD 78A IC latch-up standard.

Table 48. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	$T_A = +105\text{ }^{\circ}\text{C}$ conforming to JESD78A	II level A

### 6.3.12 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below  $V_{SS}$  or above  $V_{DDIOx}$  (for standard, 3.3 V-capable I/O pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

#### Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (higher than 5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of the  $-5\text{ }\mu\text{A}/+0\text{ }\mu\text{A}$  range) or other functional failure (for example reset occurrence or oscillator frequency deviation).

The characterization results are given in [Table 49](#).

Negative induced leakage current is caused by negative injection and positive induced leakage current is caused by positive injection.

### 6.3.18 Temperature sensor characteristics

Table 60. TS characteristics

Symbol	Parameter	Min	Typ	Max	Unit
$T_L^{(1)}$	$V_{SENSE}$ linearity with temperature	-	$\pm 1$	$\pm 2$	$^{\circ}\text{C}$
Avg_Slope <sup>(1)</sup>	Average slope	4.0	4.3	4.6	mV/ $^{\circ}\text{C}$
$V_{30}$	Voltage at 30 $^{\circ}\text{C}$ ( $\pm 5$ $^{\circ}\text{C}$ ) <sup>(2)</sup>	1.34	1.43	1.52	V
$t_{START}^{(1)}$	ADC_IN16 buffer startup time	-	-	10	$\mu\text{s}$
$t_{S\_temp}^{(1)}$	ADC sampling time when reading the temperature	4	-	-	$\mu\text{s}$

1. Guaranteed by design, not tested in production.
2. Measured at  $V_{DDA} = 3.3 \text{ V} \pm 10 \text{ mV}$ . The  $V_{30}$  ADC conversion result is stored in the TS\_CAL1 byte. Refer to [Table 2: Temperature sensor calibration values](#).

### 6.3.19 $V_{BAT}$ monitoring characteristics

Table 61.  $V_{BAT}$  monitoring characteristics

Symbol	Parameter	Min	Typ	Max	Unit
R	Resistor bridge for $V_{BAT}$	-	2 x 50	-	k $\Omega$
Q	Ratio on $V_{BAT}$ measurement	-	2	-	-
$E_r^{(1)}$	Error on Q	-1	-	+1	%
$t_{S\_vbat}^{(1)}$	ADC sampling time when reading the $V_{BAT}$	4	-	-	$\mu\text{s}$

1. Guaranteed by design, not tested in production.

### 6.3.20 Timer characteristics

The parameters given in the following tables are guaranteed by design.

Refer to [Section 6.3.13: I/O port characteristics](#) for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

Table 62. TIMx characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{res(TIM)}$	Timer resolution time	-	-	1	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 48 \text{ MHz}$	-	20.8	-	ns
$f_{EXT}$	Timer external clock frequency on CH1 to CH4	-	-	$f_{TIMxCLK}/2$	-	MHz
		$f_{TIMxCLK} = 48 \text{ MHz}$	-	24	-	MHz
$t_{MAX\_COUNT}$	16-bit timer maximum period	-	-	$2^{16}$	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 48 \text{ MHz}$	-	1365	-	$\mu\text{s}$
	32-bit counter maximum period	-	-	$2^{32}$	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 48 \text{ MHz}$	-	89.48	-	s

Table 65. I<sup>2</sup>C analog filter characteristics<sup>(1)</sup>

Symbol	Parameter	Min	Max	Unit
$t_{AF}$	Maximum width of spikes that are suppressed by the analog filter	50 <sup>(2)</sup>	260 <sup>(3)</sup>	ns

1. Guaranteed by design, not tested in production.
2. Spikes with widths below  $t_{AF(min)}$  are filtered.
3. Spikes with widths above  $t_{AF(max)}$  are not filtered

### SPI/I<sup>2</sup>S characteristics

Unless otherwise specified, the parameters given in [Table 66](#) for SPI or in [Table 67](#) for I<sup>2</sup>S are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and supply voltage conditions summarized in [Table 23: General operating conditions](#).

Refer to [Section 6.3.13: I/O port characteristics](#) for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO for SPI and WS, CK, SD for I<sup>2</sup>S).

Table 66. SPI characteristics<sup>(1)</sup>

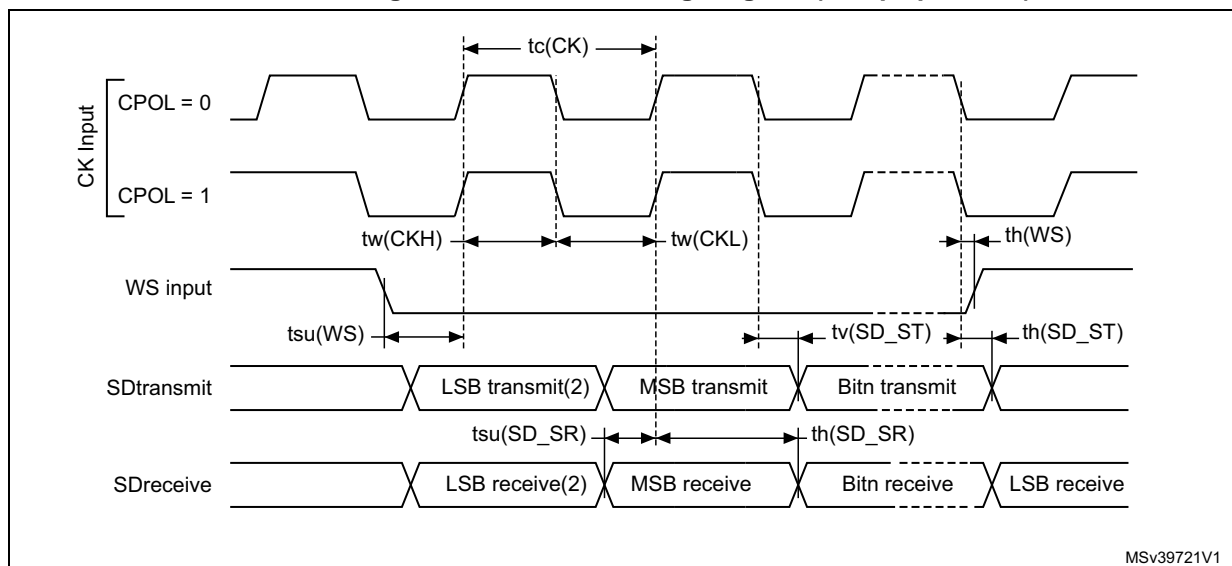
Symbol	Parameter	Conditions	Min	Max	Unit
$f_{SCK}$ $1/t_{c(SCK)}$	SPI clock frequency	Master mode	-	18	MHz
		Slave mode	-	18	
$t_{r(SCK)}$ $t_{f(SCK)}$	SPI clock rise and fall time	Capacitive load: C = 15 pF	-	6	ns
$t_{su(NSS)}$	NSS setup time	Slave mode	4Tpclk	-	ns
$t_{h(NSS)}$	NSS hold time	Slave mode	2Tpclk + 10	-	
$t_{w(SCKH)}$ $t_{w(SCKL)}$	SCK high and low time	Master mode, $f_{PCLK} = 36$ MHz, presc = 4	Tpclk/2 - 2	Tpclk/2 + 1	
$t_{su(MI)}$ $t_{su(SI)}$	Data input setup time	Master mode	4	-	
		Slave mode	5	-	
$t_{h(MI)}$ $t_{h(SI)}$	Data input hold time	Master mode	4	-	
		Slave mode	5	-	
$t_{a(SO)}^{(2)}$	Data output access time	Slave mode, $f_{PCLK} = 20$ MHz	0	3Tpclk	
$t_{dis(SO)}^{(3)}$	Data output disable time	Slave mode	0	18	
$t_{v(SO)}$	Data output valid time	Slave mode (after enable edge)	-	22.5	
$t_{v(MO)}$	Data output valid time	Master mode (after enable edge)	-	6	
$t_{h(SO)}$ $t_{h(MO)}$	Data output hold time	Slave mode (after enable edge)	11.5	-	
		Master mode (after enable edge)	2	-	
DuCy(SCK)	SPI slave input clock duty cycle	Slave mode	25	75	%

1. Data based on characterization results, not tested in production.
2. Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.
3. Min time is for the minimum time to invalidate the output and the max time is for the maximum time to put the data in Hi-Z

Table 67. I<sup>2</sup>S characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
$t_{su(SD\_MR)}$	Data input setup time	Master receiver	6	-	ns
$t_{su(SD\_SR)}$		Slave receiver	2	-	
$t_{h(SD\_MR)}^{(2)}$	Data input hold time	Master receiver	4	-	
$t_{h(SD\_SR)}^{(2)}$		Slave receiver	0.5	-	
$t_{v(SD\_MT)}^{(2)}$	Data output valid time	Master transmitter	-	4	
$t_{v(SD\_ST)}^{(2)}$		Slave transmitter	-	31	
$t_{h(SD\_MT)}$	Data output hold time	Master transmitter	0	-	
$t_{h(SD\_ST)}$		Slave transmitter	13	-	

1. Data based on design simulation and/or characterization results, not tested in production.
2. Depends on  $f_{PCLK}$ . For example, if  $f_{PCLK} = 8$  MHz, then  $T_{PCLK} = 1/f_{PCLK} = 125$  ns.

Figure 32. I<sup>2</sup>S slave timing diagram (Philips protocol)

1. Measurement points are done at CMOS levels:  $0.3 \times V_{DDIOx}$  and  $0.7 \times V_{DDIOx}$ .
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

**USB characteristics**

The STM32F078CB/RB/VB USB interface is fully compliant with the USB specification version 2.0 and is USB-IF certified (for Full-speed device operation).

**Table 68. USB electrical characteristics**

Symbol	Parameter	Conditions	Min.	Typ	Max.	Unit
$V_{DDIO2}$	USB transceiver operating voltage	-	3.0 <sup>(1)</sup>	-	3.6	V
$t_{STARTUP}^{(2)}$	USB transceiver startup time	-	-	-	1.0	$\mu s$
$R_{PUI}$	Embedded USB_DP pull-up value during idle	-	1.1	1.26	1.5	k $\Omega$
$R_{PUR}$	Embedded USB_DP pull-up value during reception	-	2.0	2.26	2.6	
$Z_{DRV}^{(2)}$	Output driver impedance <sup>(3)</sup>	Driving high and low	28	40	44	$\Omega$

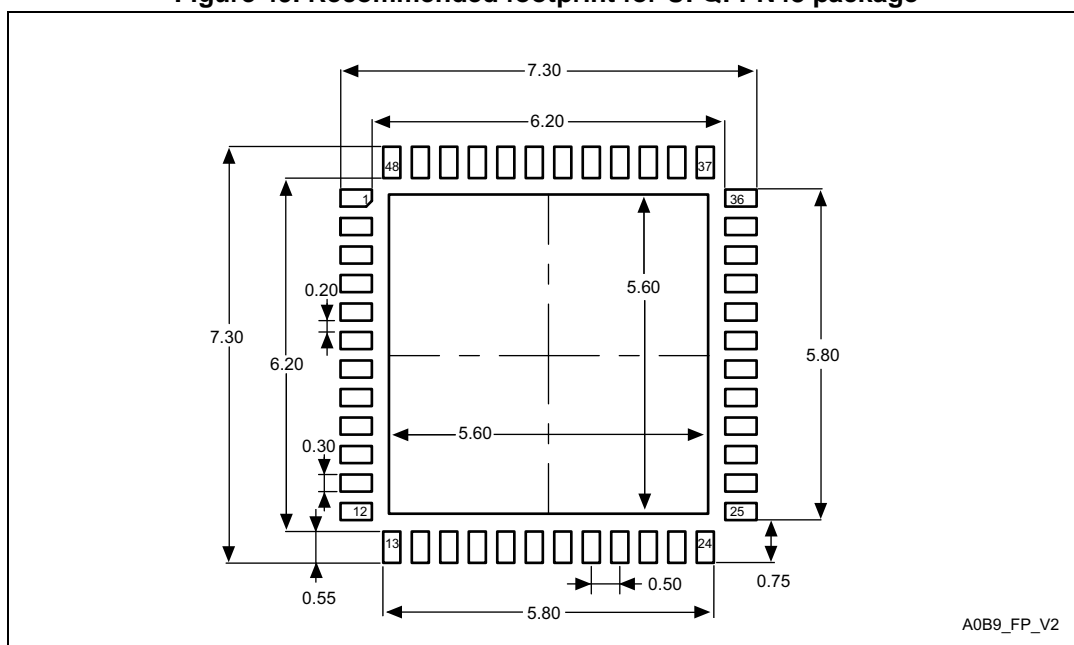
1. The STM32F078CB/RB/VB USB functionality is ensured down to 2.7 V but not the full USB electrical characteristics which are degraded in the 2.7-to-3.0 V voltage range.
2. Guaranteed by design, not tested in production.
3. No external termination series resistors are required on USB\_DP (D+) and USB\_DM (D-); the matching impedance is already included in the embedded driver.

### Table 75. UFQFPN48 package mechanical data

Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020
D	6.900	7.000	7.100	0.2717	0.2756	0.2795
E	6.900	7.000	7.100	0.2717	0.2756	0.2795
D2	5.500	5.600	5.700	0.2165	0.2205	0.2244
E2	5.500	5.600	5.700	0.2165	0.2205	0.2244
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
T	-	0.152	-	-	0.0060	-
b	0.200	0.250	0.300	0.0079	0.0098	0.0118
e	-	0.500	-	-	0.0197	-
ddd	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 49. Recommended footprint for UFQFPN48 package**



1. Dimensions are expressed in millimeters.

This is above the range of the suffix 6 version parts ( $-40 < T_J < 105\text{ }^{\circ}\text{C}$ ).

In this case, parts must be ordered at least with the temperature range suffix 7 (see [Section 8: Ordering information](#)) unless we reduce the power dissipation in order to be able to use suffix 6 parts.

Refer to [Figure 51](#) to select the required temperature range (suffix 6 or 7) according to your temperature or power requirements.

Figure 51. LQFP64  $P_D$  max versus  $T_A$

